B&T 博安通 **Shenzhen B&T Technology Co., Ltd.**
Zhongshan B&T Technology Co., Ltd.

Reliability Test Report

Item Name	NF-01-N	Item Type	2.4G Series
Tested Device	Constant temperature and humidity chamber	Test Environment	High/Low Temperature Test
Sample Quantity	2pcs	Test Type	☐Material ☐Sample ☑Finished Product ☐ Others
Test Date	2019-10-18	Report Date	2019-10-25

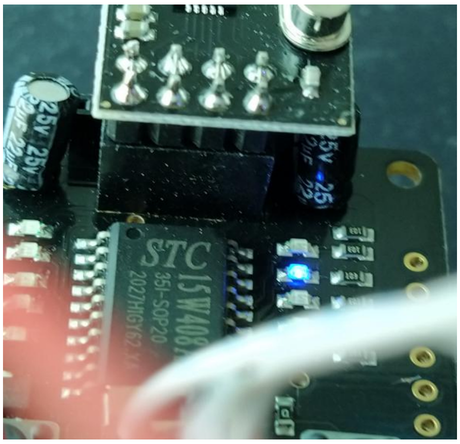
Test Items

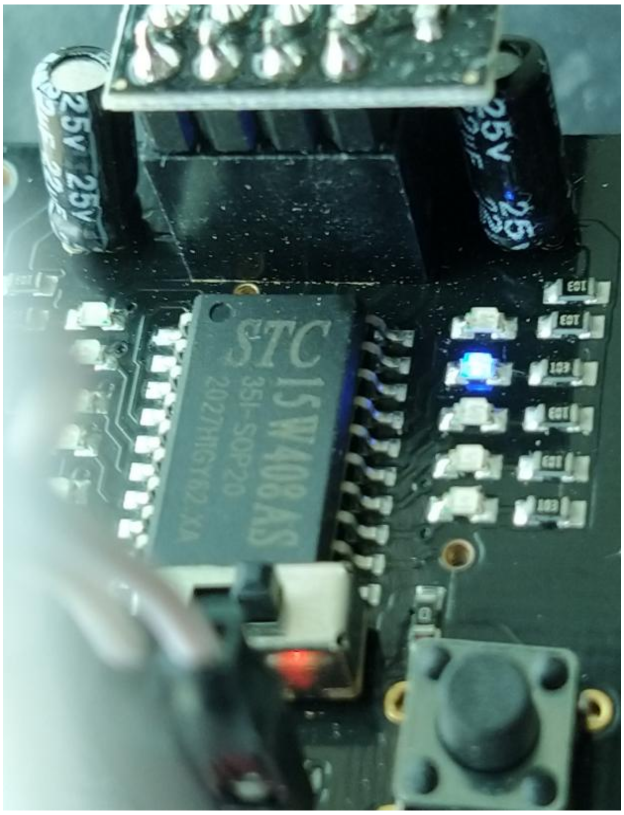
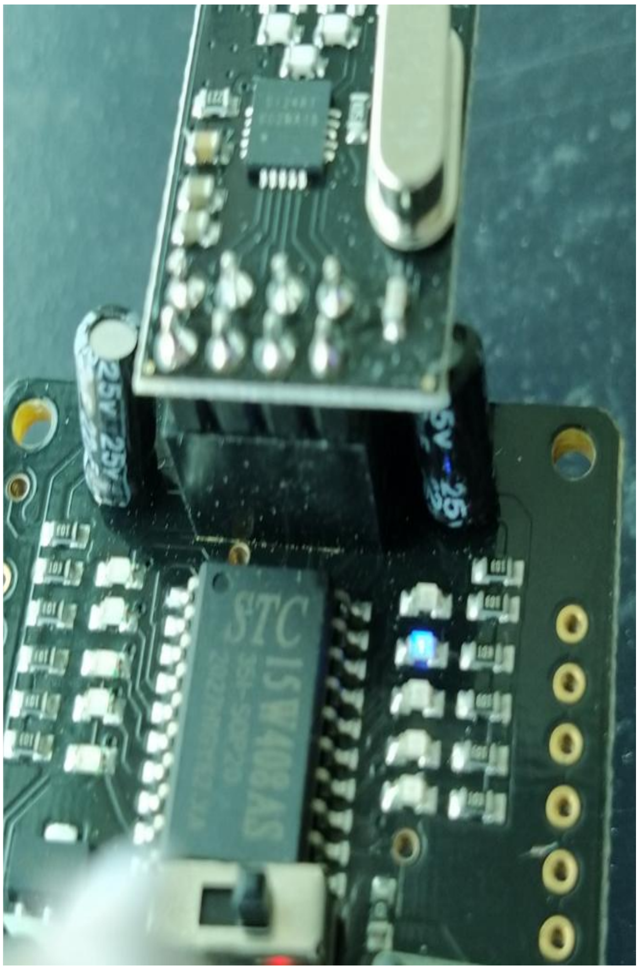
No.	Item	Test Conditions	Test Duration
1	Low temperature storage test	Test Conditions: -40℃ Test duration: 8h After restoring to -25℃ and a 1-hour soak, perform a cold start test.	12h
2	High temperature storage test	Test conditions: 100℃ Test duration: 8h After restoring to 85℃ and a 1-hour soak, perform a hot start test.	12h
3	Low temperature operation test	Test Conditions: -20℃ Test duration: 24h	24h
4	High temperature operation test	Test Conditions: 85℃ Test duration: 24h	24h

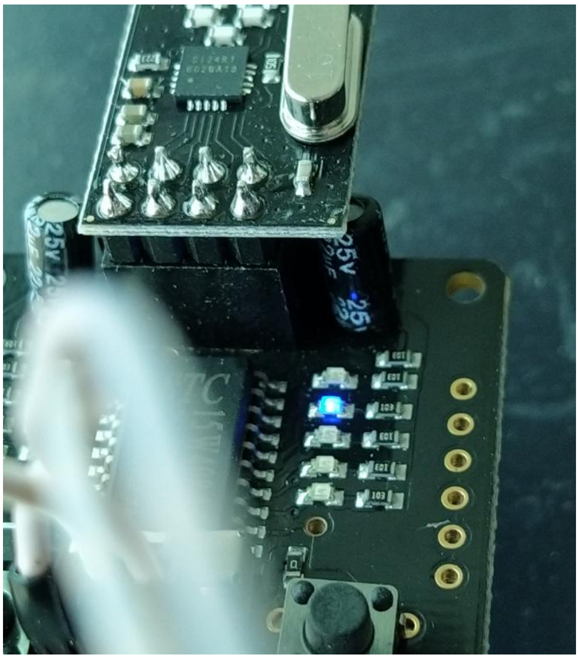
Test Environment Setup:

Confirm test samples: 2 PCS, transmit control board NRF24L01: 2 PCS, USB-to-UART serial boards: 2 PCS. 1 PCS transmits data, and 1 PCS receives. The blue LED on the MCU control board flashes when data is received. Confirm test items (low/high temperature storage, low temperature operation).

Test Result

No.	Process Description	Result	Result Description
2	Low Temperature Storage	PASS	

No.	Process Description	Result	Result Description
3	Low Temperature Operation	PASS	
4	High Temperature Storage	PASS	

No.	Process Description	Result	Result Description
5	High Temperature Operation	PASS	
Conclusion: ☑PASS; ☐FAIL			

Tested by: Chen Lingli   Reviewed by: Yuan Jingjun   Approved by: Zhou Yuming